

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KUTURIANU ET AL.	
		Examiner Ben C. Wang	Art Unit 2192	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sun Microsystems Inc., "Sun MicroSystems' JAVA Device Test Suite Helps Ensure Quality of Mobile Devices", Feb. 17, 2003, Sun Microsystems Inc., pp. 1-2
	V	Kim Topley, The Mobile Information Device Profile and MIDlets, Part 1, Oct. 1, 2003, The O'Reilly Network, pp. 1-6
	W	Kim Topley, The Mobile Information Device Profile and MIDlets, Part 5, Oct. 1, 2003, The O'Reilly Network, pp. 1-9
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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